Erratum: Surface resonance of thin films of the Heusler half-metal Co_2MnSi probed by soft x-ray angular resolved photoemission spectroscopy [Phys. Rev. B 99, 174432 (2019)]

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In the original paper, the Γ and the X points in the ARPES results on Co_2MnSi were mistakenly swapped in all figures showing experimental as well as theoretical ARPES data. Large photoemission intensity at the Fermi energy was obtained at the X and not at the Γ point. This is qualitatively in agreement with the calculated bulk Fermi surface of Co_2MnSi.

Thus, with the correct identification of the Γ and X points, the claim that surface states dominate the ARPES intensity is no longer directly supported by the qualitative intensity distribution in the experimental results.

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